


<b>Search Notes</b>  	<b>Application/Control No.</b>  10722155	<b>Applicant(s)/Patent Under Reexamination</b>  SANA ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
patent databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	3/7/2008	YJK
see enclosed for text-search strategy	3/7/2008	YJK

INTERFERENCE SEARCH			
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